

Notice of References Cited	Application/Control No. 10/025,986	Applicant(s)/Patent Under Reexamination OOYAMA ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,142,678	11-2000	Cheng, Yihao	385/79
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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